Search Notes

1	Application/Control No.	Applicant(s)/Patent under Reexamination
Ŀ	10/801,940	BAEK ET AL.
T I	Examiner	Art Unit
١,	Brian M. Healy	2883

SEARCHED						
Class	Subclass	Date	Examiner			
385	122	12/7/2005	вмн			
	123					
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INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)						
DATE	EXMR					
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